Al Defect Metrology



2D 3D Profiler BpT CLARITY PRO ™

Image surface detail in 3D at high Z-axis resolution

The BPT Clarity Pro 2D/3D Profiler is a breakthrough optical microscope that reveals surface detail in 3D with unmatched Z-axis resolution—while still performing all conventional optical imaging modes including:

Bright Field
 Dark Field
 POL
 DIC
 NIR



An easy user interface to Tag & Train your data

BpT CLARITY PRO ™ Un feye

BPT Clarity Pro Unifeye Ai is an advanced Al-powered platform designed to revolutionize the way Industrail R&D and Manufacturing Production use data. With an intuitive interface, Users can tag their data, train Al models, and generate powerful insights to support better diagnosis, treatment, innovation and higher yeild manufacturing production.



An intuitive application for training your own Ai

Sherlock BpT CLARITY PRO ™

Wafer Metrology: 2D & 3D Inspection

First system in the world to do wafer 3D & 2D analysis simultaneously

- Increase your yield with the most advanced A.I. in semiconductor metrology.
- BPT's Clarity Pro Sherlock System detects and quantifies process defects.
- Wafer metrology is the key to process control and yield enhancement.



Your Al Metrology Company



Next-Generation Glass Defect Inspection using Al



Glass Defect Inspection with sub-micron capability

GDI Clarity Pro redefines precision in glass defect inspection with cutting-edge optics and advanced surface scanning. Capable of detecting defects as small as sub-micron levels with a resolution of 2.5 µm, it delivers unmatched edge and through-surface defect analysis. Defect classification & measurement done real-time, with no throughput overhead.



IRQuickScan™

The next-generation Infrared Quick Scan™ (IRQS) System, powered by BPT Clarity Pro™ Software, delivers unmatched accuracy in detecting voids, inclusions, and strain fields across bonded wafers and advanced substrates.



AI Weld Metrology





WELDinspect **BpT** CLARITY PRO ™

BPT Clarity Pro WELDinspect is a digital microscope system with an easy to use, dedicated welding workflow system to optimize high-volume metrology requirements. The software system is designed for the Inspectis DIM-U and DIM-F inverted weld inspection systems.



